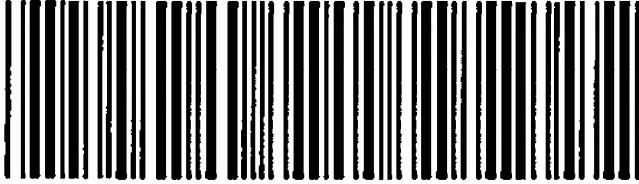


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/679,771	HAN ET AL.	
	Examiner	Art Unit	
	Richard H. Kim	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	61	10/20/2005	RHK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Text Search (349/70)- jpo,pgpub,uspat,epo-see printout	10/20/2005	RHK